

## Single N-Channel MOSFET

### ■ DESCRIPTION

SMC3322 is the N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced trench technology devices are well suited for high efficiency fast switching applications, low in-line power loss are needed in small outline surface mount package.

### ■ PART NUMBER INFORMATION

**SMC 3322 S - TR G**  
 a b c d e

a : Company name.

b : Product Serial number.

c : Package code S: SOT-23L

d : Handling code TR: Tape&Reel

e : Green produce code G: *RoHS Compliant*

### ■ FEATURES

**$V_{DS} = 30V, I_D = 6.2A$**

$R_{DS(ON)} = 20m\Omega(\text{Typ.}) @ V_{GS} = 10V$

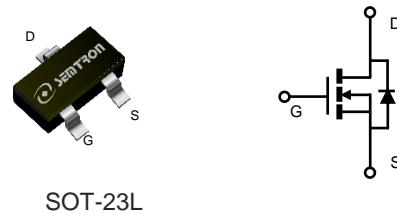
$R_{DS(ON)} = 23m\Omega(\text{Typ.}) @ V_{GS} = 4.5V$

$R_{DS(ON)} = 27m\Omega(\text{Typ.}) @ V_{GS} = 2.5V$

- ◆ Fast switch
- ◆ Low gate drive applications
- ◆ High power and current handling capability

### ■ APPLICATIONS

- ◆ Hand-Held Instruments
- ◆ Load Switch
- ◆ PWM Applications



SOT-23L

### ■ ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$ Unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DSS}$	Drain-Source Voltage	30	V
$V_{GSS}$	Gate-Source Voltage	$\pm 12$	V
$I_D$	Continuous Drain Current	$T_A=25^\circ\text{C}$	A
		$T_A=70^\circ\text{C}$	A
$I_{DM}$	Pulsed Drain Current <sup>A</sup>	24.8	A
$P_D$	Power Dissipation <sup>B</sup>	$T_A=25^\circ\text{C}$	W
		$T_A=70^\circ\text{C}$	W
$T_J$	Operation Junction Temperature	-55/150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature Range	-55/150	$^\circ\text{C}$

### ■ THERMAL RESISTANCE

Symbol	Parameter	Typ	Max	Units
$R_{\theta JA}$	Thermal Resistance Junction to Ambient <sup>C</sup>	$t \leq 10\text{s}$	85	$^\circ\text{C/W}$
	Thermal Resistance Junction to Ambient <sup>C</sup>	Steady-State	120	

**ELECTRICAL CHARACTERISTICS( $T_A = 25^\circ\text{C}$  Unless otherwise noted)**

Symbol	Parameter	Condition	Min	Typ	Max	Unit	
<b>Static Parameters</b>							
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	30			V	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.4	0.7	1	V	
$I_{GSS}$	Gate Leakage Current	$V_{DS} = 0\text{V}, V_{GS} = \pm 12\text{V}$			$\pm 100$	nA	
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 30\text{V}, V_{GS} = 0\text{V}$ $T_J = 25^\circ\text{C}$			1	$\mu\text{A}$	
		$V_{DS} = 24\text{V}, V_{GS} = 0\text{V}$ $T_J = 75^\circ\text{C}$			10		
$R_{DS(\text{ON})}$	Drain-source On-Resistance <sup>D</sup>	$V_{GS} = 10\text{V}, I_D = 6.2\text{A}$	20	24		$\text{m}\Omega$	
		$V_{GS} = 4.5\text{V}, I_D = 5\text{A}$	23	26			
		$V_{GS} = 2.5\text{V}, I_D = 3.6\text{A}$	27	32			
$G_f$	Forward Transconductance	$V_{DS} = 10\text{V}, I_D = 3\text{A}$		7		S	
<b>Diode Characteristics</b>							
$V_{SD}$	Diode Forward Voltage <sup>B</sup>	$I_S = 1\text{A}, V_{GS} = 0\text{V}$		0.7	1.0	V	
$I_S$	Continuous Source Current				2.1	A	
<b>Dynamic and Switching Parameters</b>							
$Q_g(10\text{V})$	Total Gate Charge	$V_{DS} = 15\text{V}, V_{GS} = 10\text{V}$ $I_D = 5\text{A}$		17	23	nC	
$Q_g(4.5\text{V})$	Total Gate Charge			8.7	11.7		
$Q_{gs}$	Gate-Source Charge			1.2	1.6		
$Q_{gd}$	Gate-Drain Charge			2	2.7		
$C_{iss}$	Input Capacitance	$V_{DS} = 15\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$		670	938	pF	
$C_{oss}$	Output Capacitance			54	76		
$C_{rss}$	Reverse Transfer Capacitance			45	63		
$t_{d(on)}$	Turn-On Time <sup>E</sup>	$V_{DD} = 15\text{V}, V_{GEN} = 10\text{V},$ $R_G = 3\Omega, I_D = 1\text{A}$		4.2		nS	
$t_r$				14			
$t_{d(off)}$	Turn-Off Time <sup>E</sup>			22			
$t_f$				6.6			

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged.

A. The value of  $R_{\theta JA}$  is measured with the device in a still air environment with maximum junction temperature  $T_J(\text{MAX}) = 150^\circ\text{C}$  (initial temperature  $T_A = 25^\circ\text{C}$ ).

B. The  $T_J(\text{MAX}) = 150^\circ\text{C}$ , using junction-to-ambient thermal resistance.

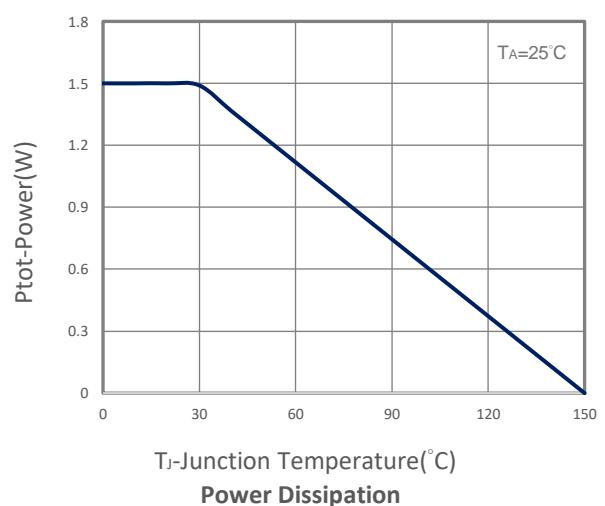
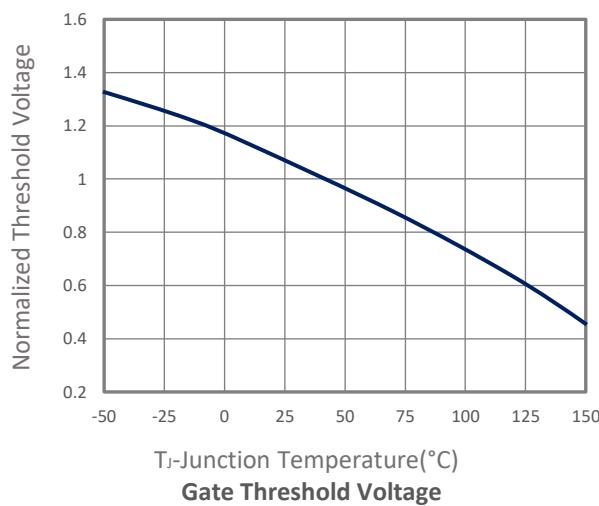
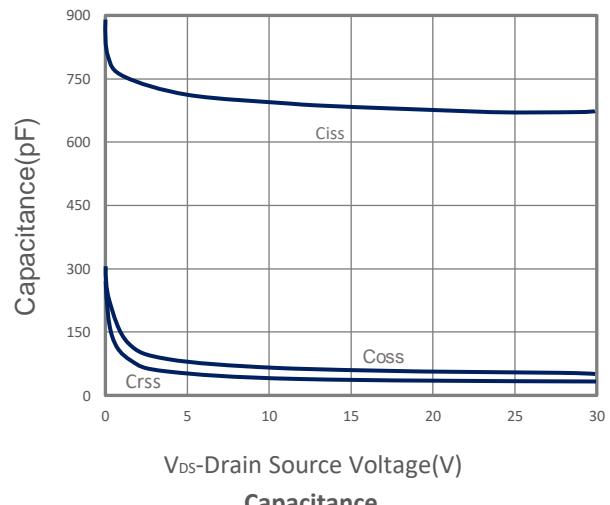
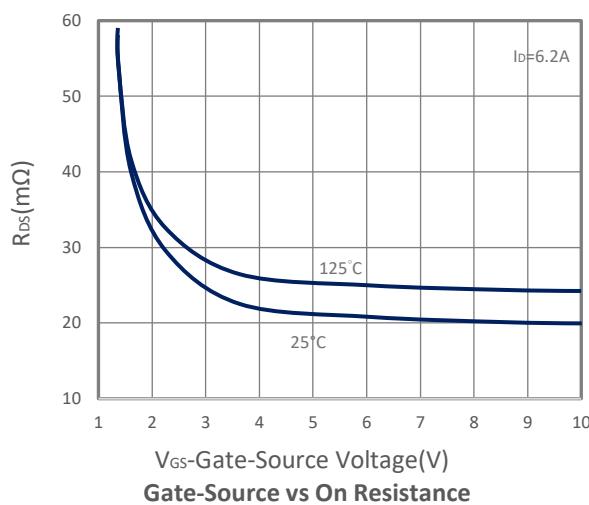
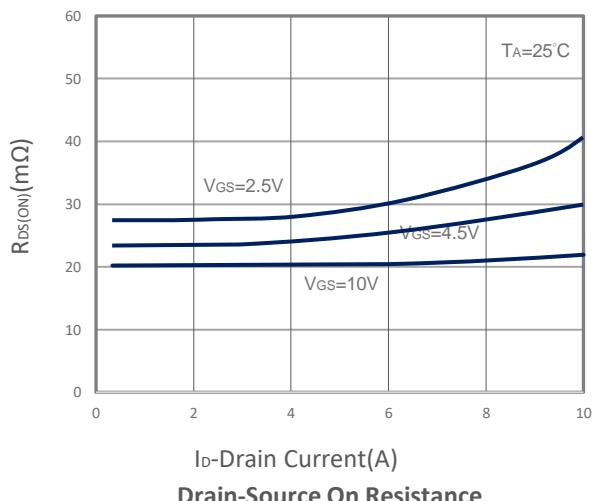
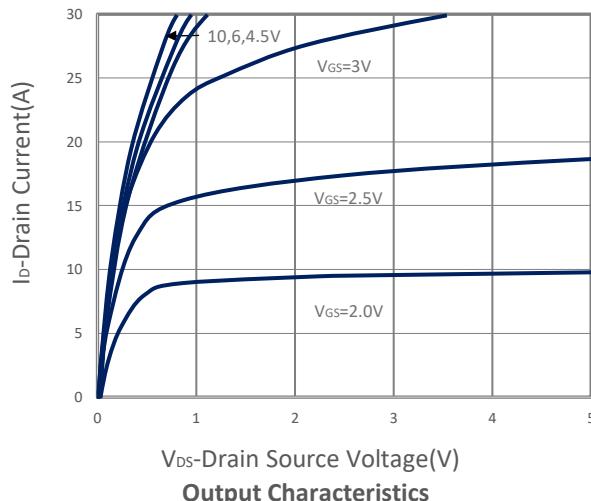
C. Surface-mounted on FR-4 board using 1 sq-in pad, 2 oz Cu, in a still air environment with  $T_A = 25^\circ\text{C}$ .

D. The data tested by pulsed, pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$

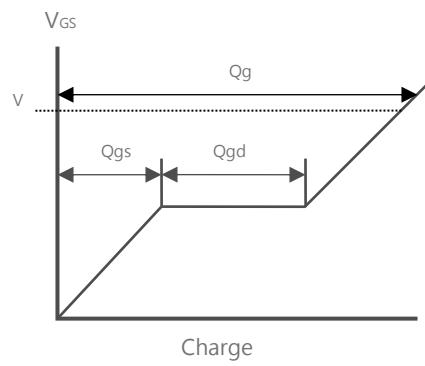
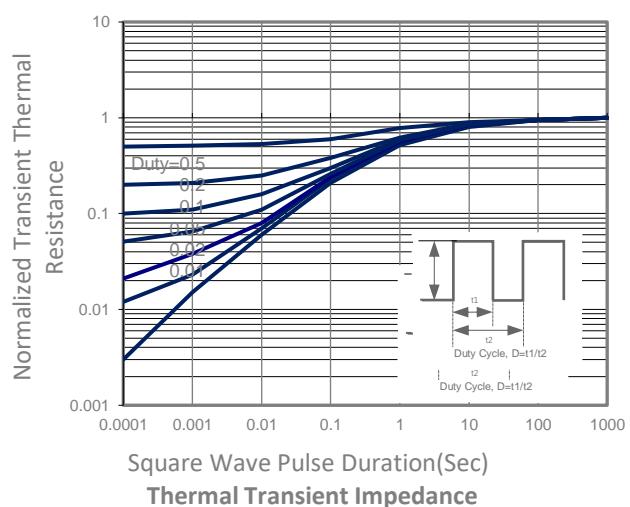
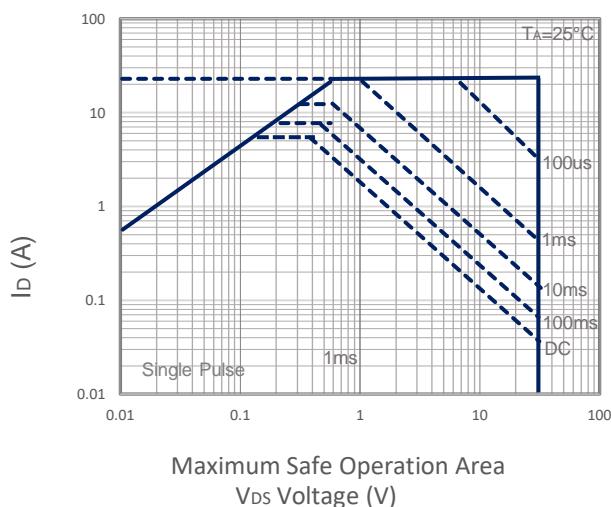
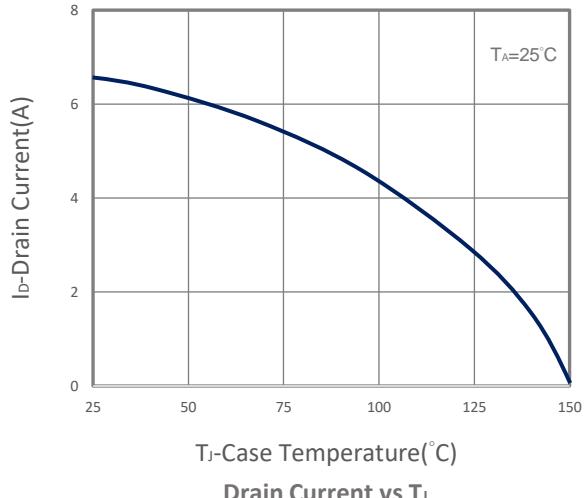
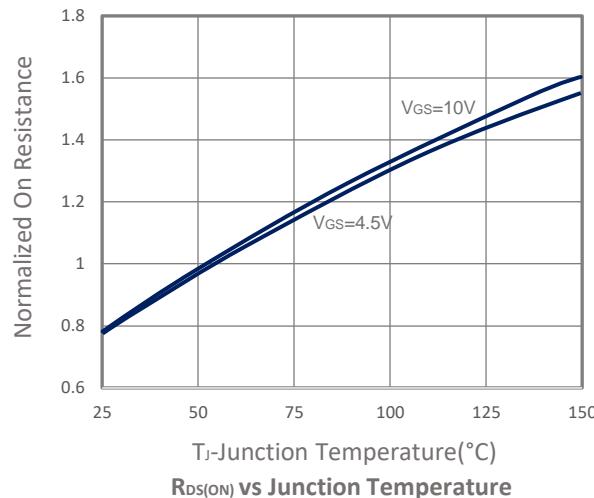
E. Pulsed width limited by maximum junction temperature.

The products and product specifications contained herein are subject to change without notice to improve performance characteristics. Consult us, or our representatives before use, to confirm that the information in this datasheet is up to date. We assume no responsibility for any infringement of patents, patent rights, or other rights arising from the use of any information and circuitry in this datasheet.

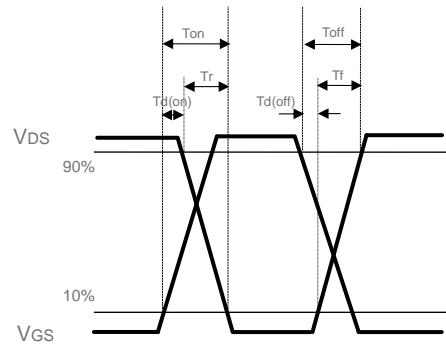
## TYPICAL CHARACTERISTICS



## TYPICAL CHARACTERISTICS

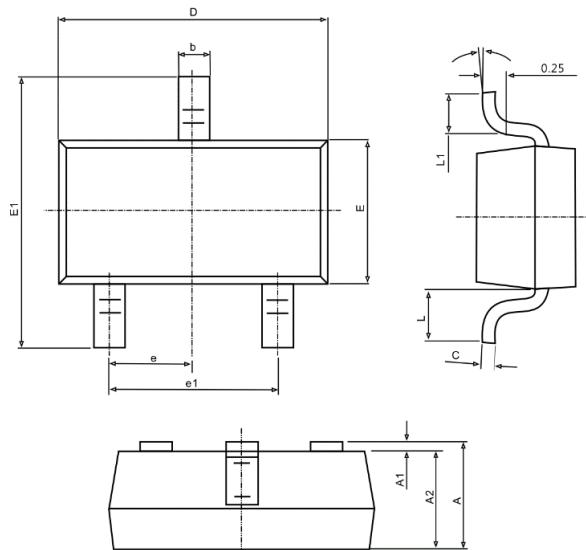


Gate Charge Waveform

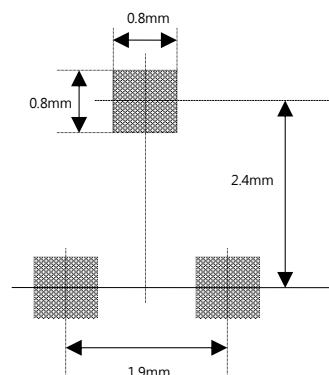


Switching Time Waveform

## SOT-23L PACKAGE DIMENSIONS



Recommended Minimum Pad(mm)



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	1.000	1.300	0.039	0.049
A1	0.000	0.100	0.000	0.004
A2	1.000	1.200	0.039	0.047
b	0.300	0.500	0.012	0.020
c	0.047	0.207	0.002	0.008
D	2.800	3.000	0.110	0.118
E	1.500	1.700	0.059	0.067
E1	2.600	3.000	0.102	0.118
e	0.950 TYP.		0.037 TYP.	
e1	1.900 TYP.		0.075 TYP.	
L1	0.250	0.550	0.010	0.022
θ	0°	8°	0°	8°